

ATT700M8G

- Trapezoidal Log Periodic Antenna
- Up to 1200 Watts
- 700MHz-8GHz
- Broad, uniform beam
- Pairs well with AR S-Series amplifiers

Features

The ATT700M8G is a wideband trapezoidal log-periodic antenna. It provides high power handling, nearly constant gain, and wide beam widths, which are nearly equal in the E and H planes. It is designed to complement AR's S-Series amplifiers and is compact, lightweight and easily mounts to a tripod using the included adapter.

The ATT700M8G is an ideal choice for applications requiring large uniform field areas, such as:

- IEC-61000-4-3
- MIL STD-461 RS103
- ISO 11451-2
- ISO 11452-2
- DO-160G Section 20
- Various other applications

The export classification for this equipment is EAR99.

NOTE: Model ATT700M12G is a lower power version of this antenna, which operates to 12 GHz.



Specifications

FREQUENCY RANGE: 700 MHz-7.5 GHz

POWER INPUT: See curve

FAR FIELD GAIN (TYPICAL): 8 dBi (See curve)

3dB BEAM WIDTH (AVERAGE):

E-Plane: 57 degrees H-Plane: 60 degrees

VSWR: 1.7:1 Typical; 3:1 Maximum

CONNECTOR: 7-16 DIN (F) WEIGHT: 1.8 kg (4 lbs)

SIZE (WxHxD): $28 \times 28 \times 56 \text{ cm} (11 \times 11 \times 22 \text{ in})$

MOUNTING: May be tripod mounted with included

mount.

AR RF/Microwave Instrumentation

160 School House Rd Souderton, PA 18964 215-723-8181

For an applications engineer call:800.933.8181

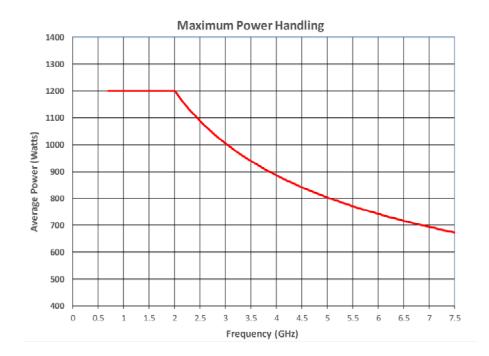
www.arworld.us

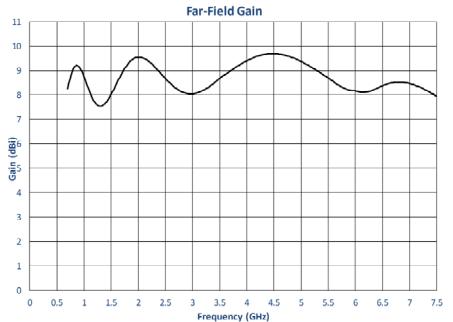


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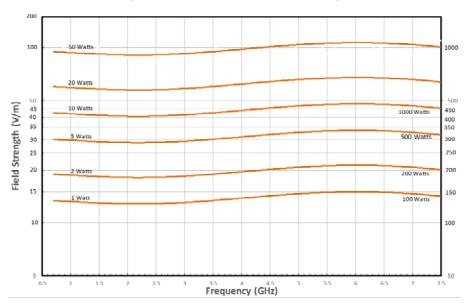
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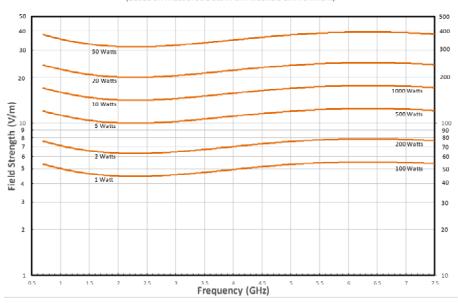
Field Strength At 1 Meter

(Based on Measured Data in an Anechoic Environment)



Field Strength At 3 Meters

(Based on Measured Data in an Anechoic Environment)



Field strengths shown are typical for free space. Proximity to conductive surfaces and the presence of the device under test will influence actual levels.